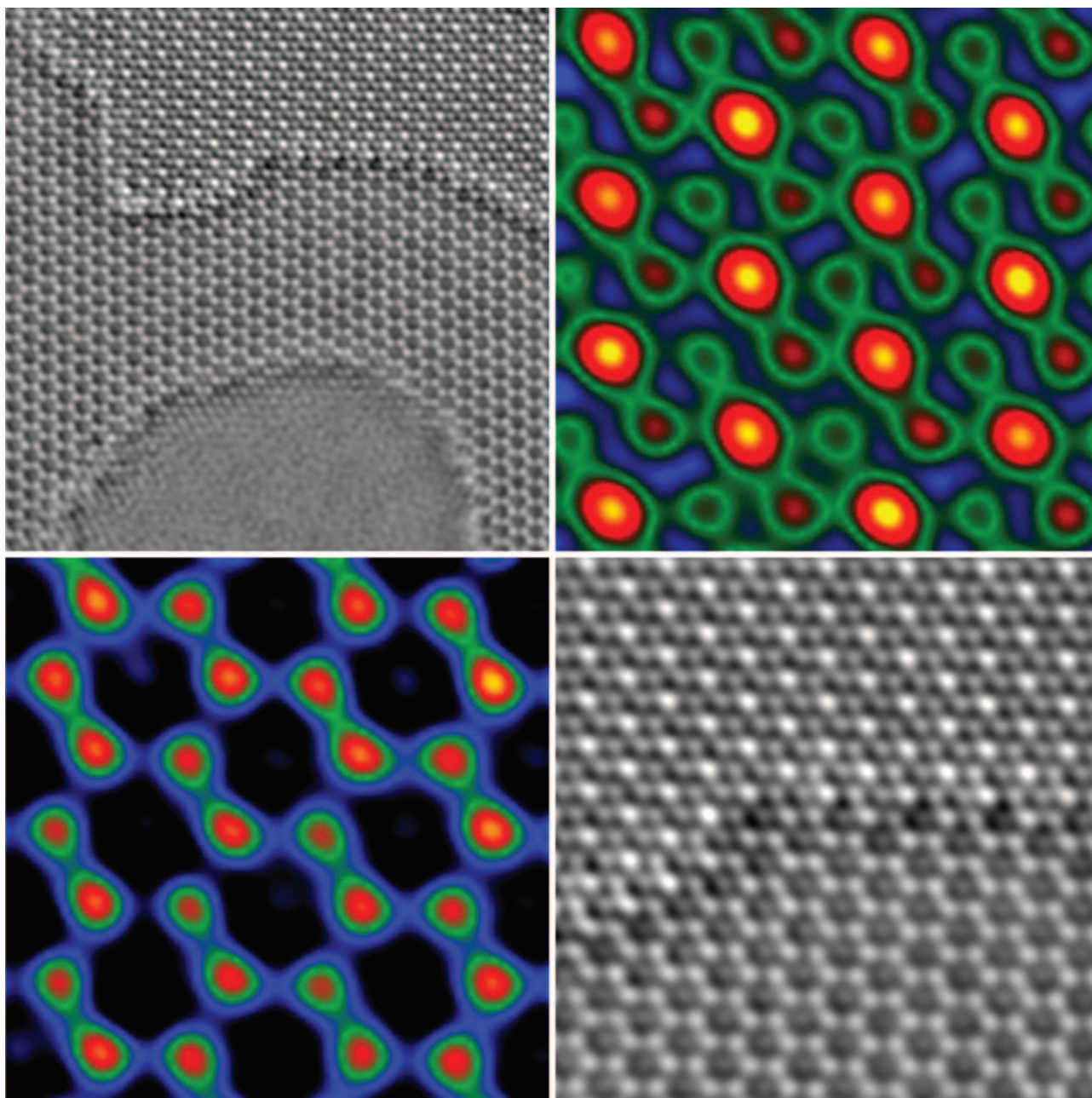


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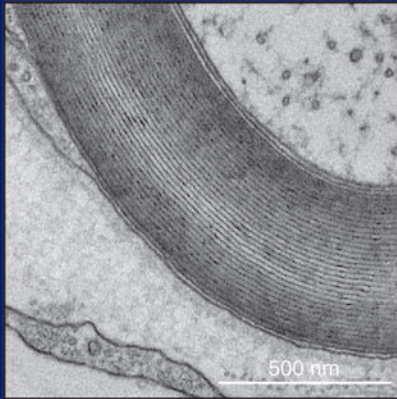
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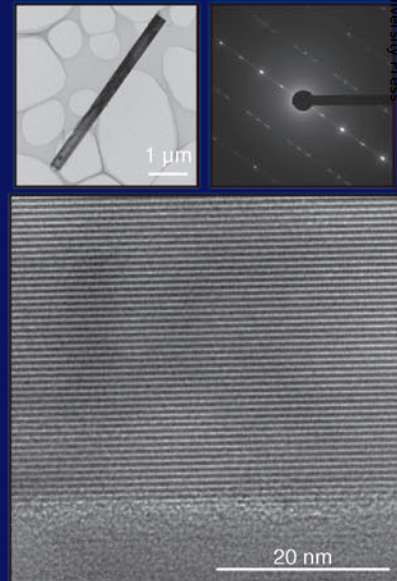
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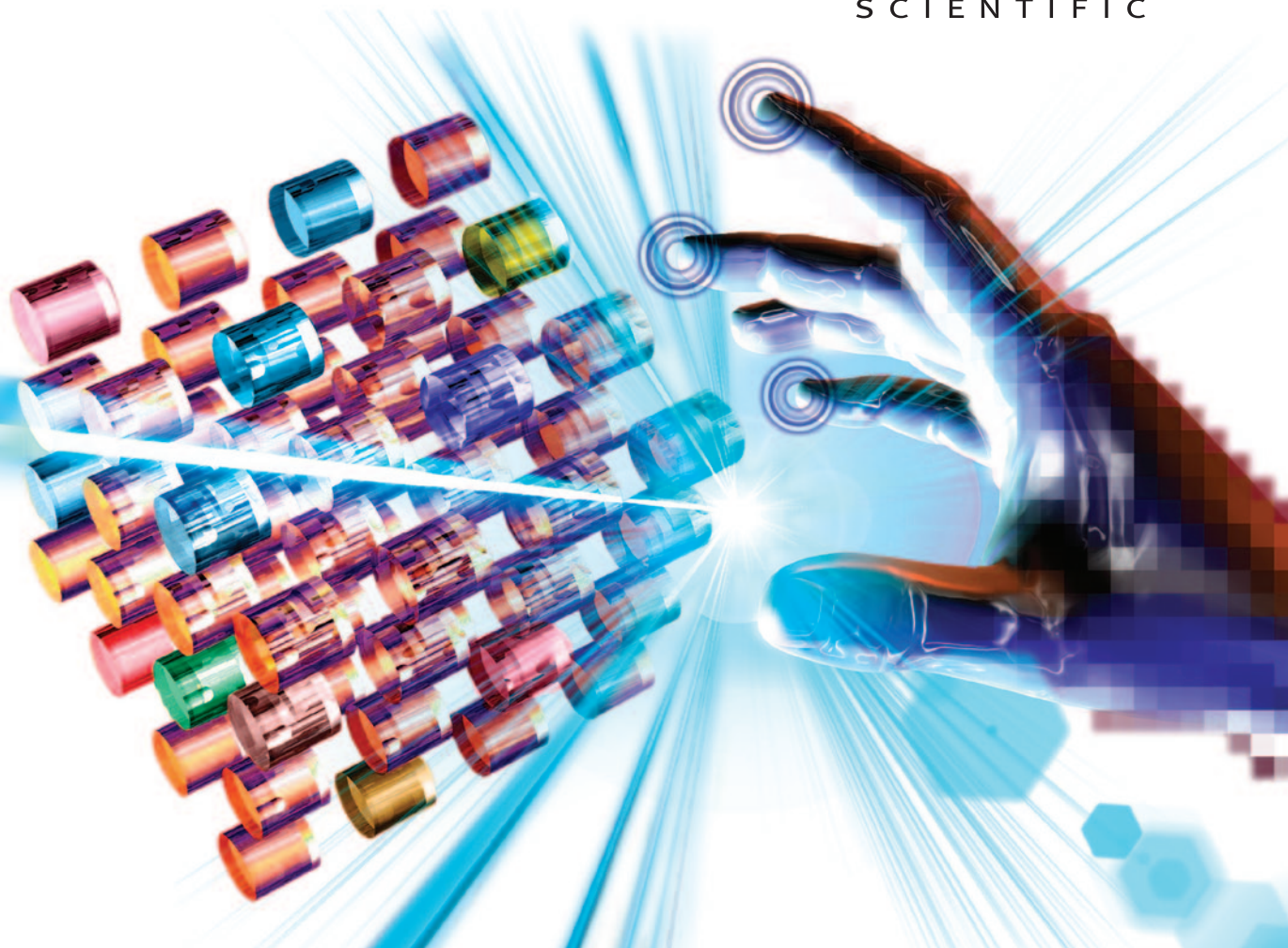
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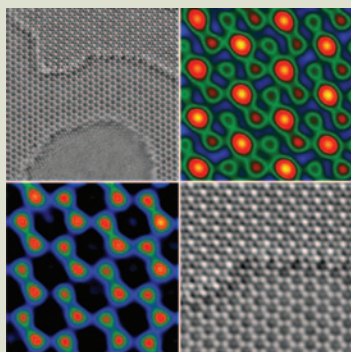
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### About the Cover



Experimental exit wave phase images of graphene sheets. Width of image at lower right = 2.73 nm.

See article by Jinschek et al.

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